

Figure 1. Dependence of average hardness, measured at indentation depth of 20 nm, on the constituent layer thickness of as-deposited and annealed $\text{Al}_2\text{O}_3/\text{Ta}_2\text{O}_5$ multilayers.

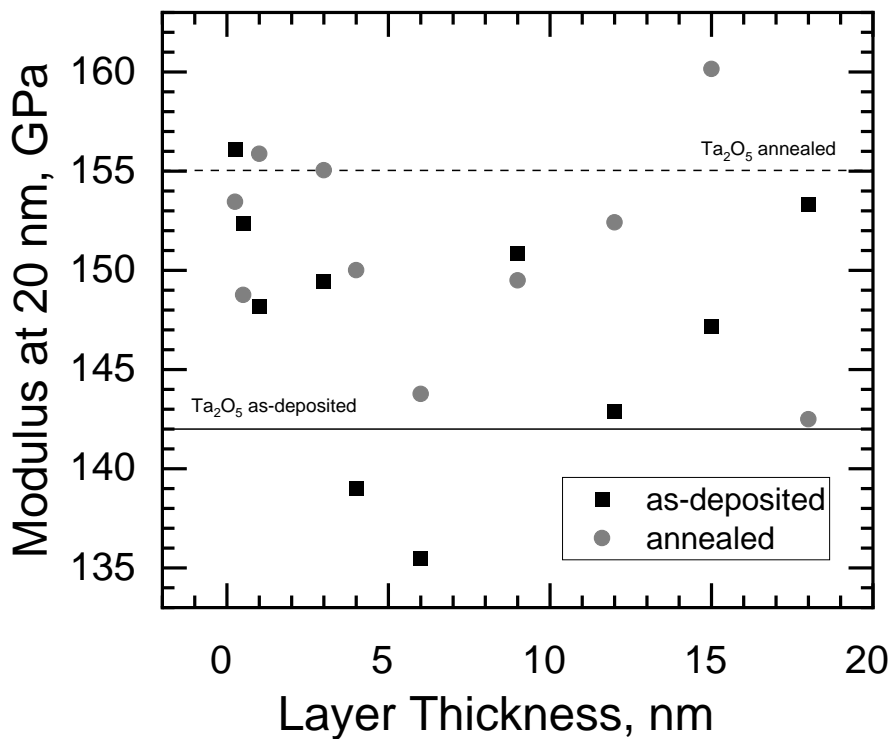


Figure 21. Dependence of average Young's modulus, measured at indentation depth of 20 nm, on the constituent layer thickness of as-deposited and annealed $\text{Al}_2\text{O}_3/\text{Ta}_2\text{O}_5$ multilayers.